CIA-RDP86-00513R000930210004-2

V.G. LITOVCHENKO S/185/60/005/003/006/020 26591 247700 D274/D303 AUTHORS: Prymachenko, V. Ye., Lytovchenko, V.G., Lyashenko, V.I. and Snitko. O.V. TITLE: The study of fast and slow electron states on a germanium surface PERIODICAL: Ukrayins'kyy fizychnyy zhurnal, v. 5, no. 3, 1960, 345-356 TEXT: The effect of an external electric field is studied on the dark conductivity (the field effect) and on the surface recombination of thin germanium plates in vacuo. The field effect was investigated at a d.c. voltage, as well as by applying rectangular pulses; this made it possible to determine separately the parameters of the fast and slow surface states. The method of investigation used is more advantageous than earlier methods; in particular, it permits studying all the surface states on a single specimen. The size of the specimens was approximately $1.5 \times 0.5 \times 0.015$ cm. The specimens Card 1/5

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were treated with CP-4 and, after measurements, with boiling H202. The germanium plates were p-type with specific resistance 40 - 50Ohm. The specimen served as one plate of a capacitor to which a d.c. voltage of 2500 v was applied as well as an a.c. voltage (rectangular pulses). The dark conductivity σ was measured by a compensation method. The change in conductivity $\Delta \sigma$ (following the application of the rectangular pulses), was measured by a special circuit. The rate of surface recombination was determined by the effective relaxation time γ of the photoconductivity, following the illumination of the middle part of the specimen by the rectangu-lar pulses of light. The relaxation of the photocurrent followed an exponential law. A diagram is given of the circuit used for the investigation. Curves are given for $\Delta \sigma$ as a function of the charge Q induced on the germanium surface. The presence of a minimum on the experimental curve $\Delta \sigma(Q)$ permitted determining the surface potential Y for each Q. The total surface potential reaches 15 kT/e \approx 0.38 eV., i.e. it is approximately equal to half the width of the forbidden germanium zone. Further, the field effect makes it

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possible to determine the charge Q_s in both fast and slow states, $(Q_s = Q - Q_o, where Q_o is the space charge)$. The surface charge in fast states changes relatively little for small Y, whereas for large Y it changes rather sharply. The dependence of Q_s on Y leads to the interpretation of the energy levels (discrete vs. continuous). The authors assume discrete interior levels; this assumption is supported by the results of recombination measurements and is also in agreement with A. Many's results (Ref. 21: J. Phys. Chem. Solids. 8, 87, 1959). Therefore, the results obtained from the field effect for the fast states are interpreted by the authors by means of a model of four discrete levels, whose parameters are given in a table; for the slow states, two discrete levels are assumed. The charge of the slow states is much greater than that of the fast states. Hence the slow states are of basic importance in screening the constant external field. Further, the dependence of the rate of surface recombination s on the surface potential Y is plotted and discussed. The fast levels are responsible for the recombination; two or even three such levels can substantially contribute to it; but, in gen-

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> **26**591 The study of fast and slow electron...

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eral, one of the fast levels is predominant in surface recombination. The values of the capture cross-sections of electrons and holes are given in the table. The measured values of the parameters of the surface levels depend on the etching method (by means of CP-4 or by H_20_2) and on whether the surfaces were freshly etched or a long time ago (their previous history); thereby the difference in the parameters is, however, not as considerable as should have been expected; the concentration of the fast states, and especially their recombination capacities show considerable dependence on the previous history of the specimens. Finally, the presence of an oxide layer on the germanium surface is considered as definitely established; this layer has a complex chemical and polycrystalline struc-The layer is the main reason for the complex system of surface states of germanium. The slow states are found on the outer surface of the oxide, being mainly determined by adsorbed atoms, whereas the fast states are on the interface Ge-oxide, being mainly due to imperfections of structure and extraneous atoms. There are 5 figures, 1 table and 36 references: 14 Soviet-bloc and 22 non-Sov-

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AUTHORS:

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ORS: Litovchenko, V. G. and Lyashenko, V. I.

TITLE: Investigation of the properties of a germanium surface at different temperatures. I. Amplitude characteristics

PERIODICAL: Fizika tverdogo tela, v. 3, no. 1, 1961, 61-72

TEXT: The properties of a real germanium surface at room temperature are well known, but those at low temperatures have hardly been investigated; and it is uncertain whether the energy distribution of the surface levels in the forbidden band is discrete or continuous. A knowledge of the temperature dependence of the electron surface-state parameters (E, N, and the trapping cross sections C_p and C_n) could clarify this problem, but the

T-functions had to be known for each single surface level in a large temperature interval. The authors investigated several parameters in the region of $170-305^{\circ}$ K, which are characteristic of the surface properties of germanium, and this paper reports on the results. The experimental method has been described in Refs. 4, 6, 7. 70-300 μ thick n-type Ge specimens of

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Investigation of the properties...

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quadratic shape have been investigated; they had been cut in the (110) plane, and had a resistivity of 20-45 ohm.cm (at 300°K), a volume lifetime of $\tau_0 \approx 250-10^3 \,\mu$ sec, and s = 100-200 cm/sec. The following measurements were made: initial change of the conductivity ΔG_0 of the specimen due to field pulses (10^{-6} sec); the change ΔG_2 after the relaxation processes; the change ΔG_3 30 soc after the field had been turned on; the proper time T_p of the short-period relaxation of the field effect, and the proper time T_e of the relaxation of photoconductivity. The dependence of these quantities upon a constant transverse electric field has been measured for a number of fixed T-values between 170 and 305°K, and the temperature dependence of kinetic characteristics without a transverse field ($E_t=0$) has been recorded. The results of the measurements are illustrated in diagrams. Fig. 1 shows ΔG_3 as a function of a charge Q_1 which had been induced on the semiconductor by a constant transverse field for n-type Ge, $n_0=5.4\cdot10^{13}$ cm⁻³ in a vacuum. Fig. 2 shows the initial bend of the band,

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 $Y_0(T)$, and the work function $\lambda(T)$ of different surface states as functions of temperature. For n-type specimens, Y_0 changes to negative values with a decreasing temperature (at $T \simeq 175^{\circ}$ K, $Y_0 \lesssim -5.5$ kT/e) but increases for p-type specimens in the positive range. Measurement of the quantities $\Delta \sigma_0$ and ΔG_2 made it possible to determine the mobility of the field effect $(\mu_{f.e.} - \Delta \sigma_p / \Delta Q_i)$. Fig. 3 shows the initial mobility $\mu_{f.e.0}$ and the quasi-steady $\mu_{f.e.2}$ as functions of the surface potential Y for various values of T. The parameters of the fast surface levels have been calculated from experimental data on $\mu_{f.e.}(Y)$; results are given in Table 1. Analogous computations were made for slow surface levels, Table 2 gives the results. The investigations showed that fast and slow surface levels have the following in common: They are discrete, show the same number, and the

concentration of the mean surface levels is about one order of magnitude smaller than that of the outer ones. The position of the fast surface energy levels does not fully agree with that of the slow levels, but this deviation is less than 2 kT/e. The concentrations of the slow surface

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"APPROVED FOR RELEASE: 03/13/2001 CIA-RDP86-00513R000930210004-2 2256 ENSTREED LEG s/181/62/004/004/001/042 B108/B102 14.7700 Litovchenko, V. G., Frolov, O. S., and Pao Shchih-mao AUTHORS : Study of long-period variations in electrical properties of TITLE: germanium surfaces Fizika tverdogo tela, v. 4, no. 4, 1962, 833 - 845 PERIODICAL: TEXT: A method of studying surface-sensitive effects in semiconductors is presented. The basic idea is to examine the long-period relaxation of conductivity and work function in the case of adsorption. A specific feature of this method is that not one but two quantities characterizing the surface space charge are to be determined by experiment, namely, the surface conductivity and surface flexure of the bands. The results of experiments on the electrical surface properties of n-type germanium were consistent with theory. The method is therefore recommended for the quantitative investigation of catalytic reactions in gases and of the electronics of metal and semiconductor surfaces. The most important results of this work (numerous numerical data on Ge are given) have been reported at the Vsesoyuznoye soveshchaniye po poverkhnosti poluprovodnikov Card 1/2

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94,000	35959 s/181/62/004/008/001/041 B125/B104	٠
AUTHORS:	Litovchenko, V. G., and Lyashenko, V. I.	
TITLE:	Adhesion of non-equilibrium carriers on the surface of germanium	
PERIODICAL:	Fizika tverdogo tela, v. 4, no. 8, 1962, 1985-1993	
of thin germa carriers was with carriers recombination temperatures. completely. small, but be signals and 1	mperature dependence of the relaxation of photoconductivity nium specimens was investigated. The adhesion of minority proved by the following results: (1) The filling of the traps produced by a constant light of high intensity excludes the mechanism of the relaxation of photoconductivity at low (2) The carriers produced by the pulse itself fill the traps At 200°K the relaxation curve is exponential when γ_{inj} is comes less exponential with increasing γ_{inj} . (3) With weak ow trap concentrations the mobile pairs responsible for photo- are extracted from the specimen by a sufficiently strong electric field. In the presence of carriers adhering to the	

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Adhesion of non-equilibrium carriers...

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surface, the excited carriers near the adhesion center are localized and cannot be extracted. (4) If injection is achieved by a rectifying contact, the relaxation of non-equilibrium conductivity has a long-wave component at very small γ_{inj} and low temperatures. This component is destroyed by weak illumination. (5) If pairs are injected into well-developed inverse or accumulation layers, long-lasting relaxation is observed at small γ_{inj} and low temperatures. (6) Long-lasting relaxation occurs primarily in the case of n-type conductivity. Further experiments indicate the occurrence of carriers on the surface, and not inside the germanium specimen. Adhesion of carriers of one sign on the surface automatically excludes carriers of the other sign from carrier conduction in the interior, and the free carriers will move only parallel to and in the vicinity of the surface. Adhesion occurs at temperatures which are the higher the thinner the specimen. The lifetime of free electrons adhering to the surface is given by

 $\tau_{n} = \frac{\frac{c^{U_{B} - K_{II}}}{C_{n} v n_{0}}}{\frac{N_{I_{0}}}{2n_{i} L} \frac{F}{\sin U_{0} - \sin U_{B}} + \frac{1 - f_{n}}{1 + \exp(E_{I_{i}} - Y_{0} - U_{B})}}$ (2)

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"APPROVED FOR RELEASE: 03/13/2001 CIA-RDP86-00513R000930210004-2 CONSISTENCE IN THE REAL PROPERTY OF THE PROPERTY OF THE 22.24·11月26日的市场的资源。24.44 图 10.000 10.000 10.000 10.000 10.000 10.000 10.000 10.000 10.000 10.000 10.000 10.000 1 s/181/62/004/008/001/041 B125/B104 Adhesion of non-equilibrium carriers... $\gamma_n = \frac{\Delta n}{\Delta n}$ with illumination it is $\tau_{n\gamma} = (C_n \upsilon n_0)^{-1} \left[\left(\frac{\Delta \sigma_1}{\Delta \sigma_2} \right)_{\gamma} + \frac{1 + \exp\left(E_{\ell\ell} - Y_s - U_B\right)}{f_{n\gamma}^{-1}} \right]^{-1} \frac{f_{n\gamma}}{e^{T_s}} \frac{1}{1 + \gamma_n}.$ (3) The notations are obviously taken from W. Shockley, W. Read. Phys. Rev., 87, 835, 1952. There are 4 figures. ASSOCIATION: Institut poluprovodnikov, AN USSR Kiyev (Institute of Semiconductors AS UkrSSR, Kiyev) December 25, 1961 SUBMITTED: Card 3/3

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• • •	9.4177 26.1512	8/181/62/004/010/045/063 B102/B112	
	AUTHORS:	Primachenko, V. Ye., Litovchenko, V. G., Lyashenko, V. I., and Snitko, O. V.	
÷	TITLE:	Minority carrier adhesion on the silicon surface	· • • • •
•	PERIODICAL:	Fizika tverdogo tela, v. 4, no. 10, 1962, 2925-2930	
	charge accumu	aper is aimed to show that under certain conditions a lation may occur on the silicon surface and that the $n = \Delta p$) may be disturbed. This is, however, contradictory	

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s/181/62/004/010/045/063 B102/B112 Minority carrier adhesion on .. only at low temperatures, but in etched silicon it may be disturbed even at room temperature. This is proved (1) by the nature of the photoconductivity relaxation of thin samples if the oscillogram shows two exponents with widely differing time constants; (2) by the constant tsh of the short-term photocurrent component being inversely proportional to the electric field applied, whereas the constant of the long-term component is independent of it; (3) by the fact that the long-term component can be caused to vanish by the usual method of trap filling; (4) by the long-term component increasing as the temperature decreases, while the short-term component decreases and almost vanishes completely, this being related to the intensified charge accumulation; in both cases $ln\tau = f(1/T)$ follows a linear course; (5) by the results obtained in a study of the kinetics of the field effect also indicating a disturbance of bipolarity. This bipolarity is also indicated by the field dependence of $\tau_{\rm sh}$ and $\tau_{\rm l}$ and (7) it is particularly pronounced in samples kept on air for a longer period of time after they had been etched. (8) Experiments on the condenser photo-emf proved that the disturbance of the photocurrent bipolarity of Si is related to a change in the surface charge. Such a Card 2/3 APPROVED FOR RELEASE: 03/13/2001 CIA-RDP86-00513R000930210004-2"

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8/181/62/004/010/045/063 Minority carrier adhesion on ... B102/B112 $\mathbf{c}_{\mathbf{n}}$ Etv $\frac{\mu_{nc}}{m} \ll 1$ and $\tau_c N_v C_p \exp(-E_{tv}/kT) \leqslant 1$ disturbance occurs when \overline{c}_p exp kT where C_p and C_n are the electron and hole trapping cross sections, E_{tv} the energy of the levels relative to the valence band, $\mu_{\rm nc}$ the electron Fermi quasilevel relative to the conduction band, τ_c the recombinative lifetime and $N_{_{\mathbf{V}}}$ the effective number of levels in the valence band. There are 3 figures. ASSOCIATION: Institut poluprovodnikov AN USSE, Kiyev (Institute of Semiconductors AS UkrSSR, Kiyev) SUBMITTED: February 6, 1962 (initially) June 12, 1962 (after revision) Card 3/3

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"APPROVED FOR RELEASE: 03/13/2001 JD/GS IJP(c) EM(m)/EMP(t)/EMP(b)L 01283-66 UR/0000/64/000/000/0020/0021 ACCESSION NR: AT5020445 50 AUTHOR: Litovchenko, V. G.; Lyashenko, V. I. 3+1 TITLE: Investigation of the natural surface of <u>silicon</u> at various temperatures SOURCE: Mezhvuzovskaya nauchno-tekhnicheskaya konferentsiya po fizike poluprovodnikov (poverkhnostnyye I kontaktnyye yavleniya). Tomsk, 1962, Poverkhnostnyye I kon-taktnyye yavleniya v poluprovodnikakh (Surface and contact phenomena in semiconductors). Tomsk, Izd-vo Tomskogo univ., 1964, 20-21 TOPIC TAGS: silicon, surface property, crystal surface, electron recombination, photoconductivity, semiconductivity ABSTRACT: In spite of the vide use of silicon in scientific research and for practical purposes, its surface properties have been insufficiently studied. The authors conduct studies at temperatures T where the forbidden zone interval on the surface is considerably broadened. Studies at low temperatures where the system of surface layers is stable can be used for solving several theoretical problems: 1) determining the nature of energy distribution in the layers (discrete or continucus); 2) the effect of temperature on the probability characteristics of capture by a Card 1/3

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local electron or hole center; 3) the effect of temperature on the other parameters of the levels: energy state E_i and concentration N_i 4) the effect of temperature on band curvature ϕ_g and work function χ must be known for design purposes. The silicon surface was studied in the 180-620°K range. The authors measured the fiel: effect at constant voltage, the pulsed field effect for small signals and photoconductivity in darkness and under constant illumination. At low temperatures, ϕ_g is usually shifted toward the region of minus values in p-silicon, becoming approximately constant at the lowest temperatures. Sometimes ϕ_{g} const throughout the entire temperature range. The differences are caused by differences in surface layer systems. It was found that N const and the E_i decreases linearly with a reduction in T. The data support a discrete model for fast surface levels. Charge capture is an important factor in photoconductivity at low temperatures, while the recombination mechanism is the sole factor ordinarily at room temperature. There is little change in the fast surface level system up to 100°C. There is a considerable change in the system of surface electron states after heating for 0.5-2.5 hours at 100°C in a vacuum: N_t may be changed by a factor of v10, and the same applies to the speed of surface recombination. The changes are stable, only slightly sensitive to ambient atmospheric conditions, and almost completely restored when the system is re-evacuated after admitting air into it. The effect of temperature on the electron system

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ABSTRACT unipolar <u>con</u> case when t surface), o	The kinetic and iductivity in the r tie semiconductor r in the bulk. Th	may be degend e relaxation is e centers, line	irated at the indetermined build dislocation	y capture on trap s, etc. Relation	s located ships s light-
ABSTRACT unipolar <u>con</u> case when t surface), o	The kinetic and <u>iductivity</u> in the r lie semiconductor	may be degend e relaxation is e centers, line	irated at the indetermined build dislocation	y capture on trap s, etc. Relation	s located ships s light-

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AUTHOR: Litovchenko, V. G.: Gorban', A. P.; Kovbasynk, V. P.	
TITLE: Investigation of the effect of edhesion of photocarriers on the surface of	
silicon SOURCE: Fizika tverdogo tela, v. T. no. 2, 1965, 565-572	· / ·.
TOPIC TAGE: adhesion, photoconductivity, photoconductivity relaxation, surface	
ABSTRACT: The purpose of the investigation was to establish the electronic and chemical-structure surface states for which the minority carriers can adhere to the chemical-structure surface states for which the minority carriers can adhere to the surface of silicon, to determine the detailed mechanism of the electronic exchanges	
of the intrinsic photoconductivity, and to ascurtain which of the investigated or of the intrinsic photoconductivity, and to ascurtain which of the investigated or investigated by the service adhesion effect. The test procedure was	
based on violating the equilibrium of a small dection of the forther the kinetics of surface and investigating the kinetics of the photoconductivity and the kinetics of the field effect. The surface potential was changed by supplying to the surface	
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L 38615-65 AP5005:02 ACCESSION NR: large amplituge rectangular electric-field pulses. The measurements were made in VECUUM (~10-6 torr) on thin semples (~ 300u) of I-type silicon (~ 103 ohm-cm, (inv 102 usec), cut along the (111) plane and etched. A detailed description of the procedure and the equipment, and of data on the band model of the real surface of the silicon, is contained in a separate article (UFZh v, 10, no. 2, 1965). The results show that the form of the photoconductivity relaxation may be connected with the character of the space-charge surface layer. A model is proposed for the electronic transitions, according to which the accumulation of carriers in the band is due to the "delayed remombination" lev1. According to this model, illumination transfers the "delays(recombination" levels into pure combination levels, and therefore the long-time relaxation is eliminated by illumination. When the tempersture is increased, to the contrary, the number of levels going over to the "delayed recombination" levels increases, in agreement with experiment. It is shown that an appreciable effect on the formation of adhesion centers is due to the "We thank Professor Y. I. Lyashenko, presence of water molecules on the surface. K. D. Glinchuk, C. V. Snitko, and V. Fe. Primachunko for s. discussion of the re-Orig. art. has: 3 figures, 3 formulas, and 2 tables. ASSOCIATION: Institut: pojuprovodnikov AN Ukr88R, Kinv (Institute of Saniconductor sults. to at these Cerd 2/3

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L 29956-66 ACC NR: AP6012476 AUTHOR: Litovchenko, V. G.; Kovbasyuk, V. P.; Sviridenko, P. T. AUTHOR: Litovchenko, V. G.; Kovbasyuk, V. P.; Sviridenko, P. T. CRG: Institute of Semiconductors, AN UkrSSR, Kiev (Institut poluprovodnikov AN UkrSS ORG: Institute of Semiconductors, AN UkrSSR, Kiev (Institut poluprovodnikov AN UkrSS SOURCE: Fizika tverdogo tela, v. 8, no. 4, 1966, 1147-1155 SOURCE: Fizika tverdogo tela, v. 8, no. 4, 1966, 1147-1155 TOFIC TAGS: silicon, ir photoconductor, crystal surface, surface property, ir absor tion, resonance absorption, impurity center, activation energy tion, resonance absorption, impurity	rp oom
ABSTRACT: The spectra of surface infrared photoconductivity were investigation of temperature and at 120K using chemically etched surfaces of p- and n-type silicon. temperature and at 120K using chemically etched surfaces of p- and n-type silicon. The purpose of the investigation was to establish the type of energy distribution of the surface traps, to determine the activation energy of the centers, to estimate the surface traps, to determine the activation on the type of photon absorption by their concentration, and to obtain information on the type of photon absorption by the centers (resonant or nonresonant). The spectra were obtained with an IKS-12 sp the centers (resonant or nonresonant). The intensity was varied with the aid of round trometer with slit width 0.05-2 mm. The intensity was varied with an incandesce diaphragms calibrated for each wavelength. The illumination was with an incandesce lamp, square-wave modulated at 9 cps. The samples were in the form of thin plates lamp, square-wave modulated at 9 cps. The samples were in the form of thin plates lamp, square wave modulated at 9 cps. The samples were in the form of thin plates lamp, square wave modulated at 9 cps. The samples were in the form of thin plates lamp, square wave modulated at 9 cps. The samples were in the form of thin plates lamp, square wave modulated at 9 cps. The samples were in the form of thin plates lamp, square wave modulated at 9 cps. The samples were in the form of thin plates lamp, square wave modulated at 9 cps. The samples were in the form of thin plates lamp, square wave modulated at 9 cps. The samples were in the form of thin plates lamp, square wave modulated at 9 cps. The samples were in the form of thin plates lamp, square wave modulated at 9 cps. The samples were in the form of thin plates at a several maxima, a set of clearly pronounced "ledges" at medium wavelength, and a several maxima, a set of clearly pronounced "ledges" at medium wavelength, and a	bec- l ent lu- ob-
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smooth rise in photoconductivity wi. 1 decreasing wavelength to the absorption edge. At low temperatures the spectra exhibited a more monotonic behavior. The presence of the structure in the spectra indicates a discrete character of the energy distribution for the main surface traps. The activation energies calculated from the spectra agreed with those obtained from the differential field effect. The dependence of the infrared conductivity of the illumination, its kinetics, and the influence of illumination with white light on the spectra and on the kinetics were also investigated. In the latter case it is possible to determine the surface potential without knowing the minimum of the surface conductivity. It is concluded that detailed investigations of the spectra of surface infrared conductivity and its kinetics as well as its temperature and field dependence, can serve as an effective new method of investigating the properties of surface centers and the laws governing the nonequilibrium processes which occur in the space-charge region. Orig. art. has: 6 figures and 3 formulas. OTH REF: 007 ORIG REF: 015/ SUBM DATE: 01Sep65/

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	L 06264-67 EWT(1)/EWT(m)/EWP(t)/ETI IJP(c) JD	
	ACC NR: AP6030975 SOURCE CODE: UR/0181/66/008/009/2765/2767	
1 (* (* 4	AUTHOR: Kovbasyuk, V. P.; Litovchenko, V. G.	•
	ORG: Institute of Semiconductors, AN UKrSSR, Kiey (Institut poluprovodnikov AN	
	UkrSSR)	
	TITLE: Effect of external electric field on the infrared photoconductivity of "pure"	
Ì	sillicon 27	
	SOURCE: Fizika tverdogo tela, v. 8, no. 9, 2765-2767	
	TOPIC TAGS: photoconductivity, electric field, IR radiation	
المت المادية محاجم المعاد ومحاجر المحاجر وم	ABSTRACT: The article describes the effect of an external electric field on the IR photoconductivity observed in thin (~0.5 mm) samples of n- and p-type silicon containing impurities in amounts less than 10^{13} cm ⁻³ . This effect is important in determining the mechanisms of formation of extrinsic photoconductivity. The field E was 5×10^5 V/cm, and the photoconductivity was measured in the 0.9-3 μ wavelength range	
Į.	at 297 %. IR photoconductivity spectra obtained in the absence and presence of the external field are compared with the spectrum of surface traps obtained from the dif-	
	ferential field effect. It is shown that in most cases the photoactive absorption of IR light on surface centors is due to "impurity center - majority carrier band" tran- sitions. Orig. art. has: 1 figure and 2 formulas.	•
*	SUB CODE: 20/ SUBM DATE: 22Feb66/ ORIG REF: 007/ OTH REF: 001	
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「「「「「「「」」」」「「「」」」」」「「」」」」」」「「」」」」」」」」」	AUTHOR: Litovchenko, V. G., Frolov, O. S., Vengris, S. A., Serba, A. A. Sadovnichiy, A. A.	
945 - X1	ORG: none	9
1	TITLE: Photoelectric characteristics of the capacitance of a surface charge varicap	
	SOURCE: Radiotekhnika i elektronika, v. 12, no. 1, 1967, 76-86	,
	TOPIC TAGS: varactor diode, silicon semiconductor, photoelectric property	
	ABSTRACT: The photoelectric properties of the spacecharge capacitance of metal- oxide-silicon (MOS) varicaps were studied. The varactors were made from rec- tangular high-resistance ($5 \times 10^1 - 5 \times 10^2$ ohms/cm) photosensitive	
:	silicon chips (dimensions, 15 x 5 x 0.0 minute alectrode $\alpha (10^{-2} - 1 \text{ mm}^2; \text{thick})$	
	ness of the oxide, 700.3747. The only revel of injunction of electron-hole pairs ductance measurements from which the level of injunction of electron-hole pairs	
L.	Δ n was calculated. The varied with platinum filters. The capacitance of the samples was the intensity was varied with platinum filters.	
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"JUNCLEMENTO, V.N.
LITOVCHENECO, V.N.
Studying the slide and wrapping mechanisms of an automatic scap
wrapping machina, Trudy KIPP no.16:83-86 '57, (WIBA 12:7)
wrapping machinas)
. Kraanodarskiy institut plehchevoy provyellennosti, Mekhanicheskiy fakul'tet, kafedra tekhnicheskoy mekhaniki.
(Wrapping machinas)

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"APPROVED FOR RELEASE: 03/13/2001 CIA-RDP86-00513R000930210004-2 也沒有時期最高級同時期的影響 LITOVCHENKO, V.P. AID P - 2971 : USSR/Electricity Subject Pub. 29 - 21/35 Card 1/1 : Litovchenko, V. P., Eng. Author Preparation of switchboard panels from asbestoscement sheeting, textolite, and hetonax : Title Periodical : Energetik, 5, 26-27, My 1955 The author describes the method of removing the hygroscopic capacity of such panels. : Abstract Institution : None Submitted : No date

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LITOVCHENKC, V.P.

in internation

Determining the position of a normal to the profile of a cam in linear motion. Trudy KIPP no.16:81 '57. (MIRA 12:7)

1. Krasnodarskiy institut pishchevoy promyshlennosti, Mekhanicheskiy fakul'tet, kafedra tekhnicheskoy mekhaniki. (Machinery, Kinematics of)

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CIA-RDP86-00513R000930210004-2

-----s/2789/64/000/054/0004/0052 ACCESSION NR: AT4038390 AUTHOR: Belyayev, V. P.; Beltadze, T. G.; Litovchenko, V. P.; Litvinova, V. D.; Lominadze, V. P.; Pinus, N. Z.; Sofiyev, Ye. M.; Shur, G. N. TITLE: Some results of experimental studies of atmospheric turbulence by means of radiosondes SOURCE: Tsentral'naya aerologicheskaya observatoriya. Trudy*, no. 54, 1964. Atmosfernaya turbulentnost' (Atmospheric turbulence), 4-52 .TOPIC TAGS: meteorology, atmospheric turbulence, radiosonde, air route turbulence 'ABSTRACT: A description is given of methods and equipment for measuring air turbulence over Moscow, Sukhumi (Caucasus), and 1 Tashkent (Kazakhstan). One of the noteworthy features of the method is the synchronization of measurements of air turbulence with Cord 1/3

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CIA-RDP86-00513R000930210004-2

ACCESSION NR: AT4038390 such parameters as air temperature, humidity, pressure, wind velocity and wind direction. Turbulence was measured mostly by balloon-borne radiosondes with an A-22-III accelerometer attached. Sufficient data have been collected (457 radiosonde ascents in 1961-62) to determine a turbulence pattern over the aforementioned localities. Turbulence occurs with the highest frequency in the 1-2 km ground layer, it then decreases reaching a minimum at 6-7 km and then reaches a maximum again at 10-12 km. Data were analyzed to determine other turbulence characteristics depending on location, season, altitude, etc. It was noted that turbulence generally depends on thermal and dynamic stratification in the atmosphere. and frequently occurs during pronounced vertical wind and temperature gradients. Two turbulent layers are frequently observed: one above the jet stream and one below it. Turbulence is minimal on the jet stream level. It was also observed that over Moscow and Sukhumi the turbulent layer seldom exceeds 200-400 m and only over Tashkent at 5-7 km is it ever more than 1000 m thick. The experimental work was carried out by the Central Aerological Observatory, Moscow. Also ł Card 2/3

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"APPROVED FOR RELEASE: 03/13/2001 CIA-RDP86-00513R000930210004-2 的形式的目的活动的特殊和可能的原则是在一个 1 cited are turbulence data for the United States and data collected ACCESSION NR: AT4038390 cicea are curbulence data for the united States and data collected by E. A. Hyde (1954) for air routes from London to the Far East and back, and London to North Africa. Orig. art. has: 12 tables, 20 figures, and 36 formulas figures, and 36 formulas. ASSOCIATION: none 00 ENCLI DATE ACQ: 11Jun64 SUBMITTED: 00 006 . **OTHER:** NO REF SOV: 019 SUB CODE: ES . . . Card 3/3

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L <u>L301-66</u> EWT(1)/FCC GW ACCESSION NR: AT5022877	UR/27851/65/000/063/0031/0036 551.551.551.557.5
AUTHORS: Krupchatnikova, T. P.; Litovche 44,55 TITLE: Computing the distribution of tur	44,55
SOURCE: Tsentral'naya aerologicheskaya c Voprosy dinamiki atmosfery (Problems of a	bservatoriya. Trudy, no. 63, 1965. tmospheric dynamics), 31-36
TOPIC TAGS: turbulence coefficient deter turbulent jet, jet stream, approximation	mination, turbulence, turbulent flow, method 12,44.55
ABSTRACT: The authors study the problem lence in jet streams. The investigation the wind field in the horizontal plane. of the system of equations for jet stream	takes into account the nonuniformity of
$\frac{\partial \mu}{\partial t}$, $\frac{\partial v}{\partial t}$, $\mu \frac{\partial u}{\partial x}$, $\mu \frac{\partial v}{\partial x}$, $\nu \frac{\partial \mu}{\partial y}$ and $v \frac{\partial v}{\partial y}$ members of the equation of motion; a furt the geostrophic wind is essentially invar motion under these circumstances may be	iant with altitude. The equations of
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DIKOV, V.A., st. inzh.; KOLKOTIN, N.M., st. inzh.; KUVYRKIN, N.I., st. inzh.; <u>LITOVCHENKO, Ya.A.</u>, st. inzh.; SULOTSKIY, B.P., st. tekhnik; ABDULINA, Kh.M., st. tekhnik; SHIROKCVA, G.M., red.izd-va; MIKHEYEVA, A.A., tekhn. red.

[Instructions (U 5-62) for the major repair of machinery used in construction] Ukazaniia po kapital'nomu remontu mashin, zaniatykh v stroitel'stve (U 5-62). Moskva, Gosstroiizdat. No.l. [Requirements and general technical specifications for the major repair of machinery] Trebovaniia i obshchie tekhnicheskie usloviia po kapital'nomu remontu mashin. 1962. 14 p. (MIRA 16:3)

1. Akademiya stroitel'stva i arkhitektury SSSR. Institut organizatsii, mekhanizatsii i tekhnicheskoy pomoshchi stroitel'stvu. (Construction equipment---Maintenance and repair)

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DIKOV, V.A., st. inzh.; KUVYRKIN, N.I., st. inzh.; LITOVCHENKO, Ya.A., st. inzh.; SULOTSKIY, B.P., st. tekhnik; ABDULINA, Kh.M., st. tekhnik; ZAYTSEV, B.D., otv. za vypusk; SHIROKOVA, G.M., red. izd-va; MIKHEYEVA, A.A., tekhn. red.
[Instructions U5-62 for the major repair of machinery used in construction] Ukazaniia po kapital'nomu remontu mashin, zaniatykh v stroitel'stve (U 5-62). Moskva, Gosstroiizdat. No.2. [Technical specifications for the major repair of truck-mounted cranes and loaders; the K-32 LAZ-690 and K-51 truck-mounted cranes and the T-107 loader] Tekhnicheskie usloviia na kapital'nyi remont avtomobil'nykh kranov i pogruzchikov; avtokrany K-32, LAZ-690 i K-51 pogruzchiki T-107. 1963. 119 p. (MIRA 16:6)

1. Akademiya stroitel'stva i arkhitektury SSSR. Institut organizatsii, mekhanizatsii i tekhnicheskoy pomoshchi stroitel'stvu. (Construction equipment---Maintenance and repair)

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DIKOV, V.A., st. inzh.; KUVYRKIN, N.I., st. inzh.; LITOVCHENKO, Ya.A., st. inzh.; SULOTSKIY, B.P., st. tekhnik; ABDULINA, Kh.M., st. tekhnik; SHIROKOVA, G.M., red. izd-va; MIKHEYEVA, A.A., tekhn. red.

[Instructions for the overhauling of construction machinery [U 5-62)] Ukazanita po kapital'nomu remontu mushin, zaniatykh v stroitel'stve (U 5-62). Moskva, Gosstroiizdat. No.3. [Specifications for the overhauling of road machinery (D-144, and D-265 motor graders, D-159B and D-271 bulldozers, D-211 and D-260 motor rollers, D-183B and D-222 scrapers),] Tekhní heskie usloviia na kapital'nyi remont dorozhnykh mashin (avtogreidery D-144 i D-265, bul'dozery D-159B i D-271, katki motornye D-211 i D-260, skrepery D-183B i D-222). 1963. 309 p. (MIFA 16:8)

1. Akademiya stroitel'stva i arkhitektury SSSR. Institut organizatsii, mekhanizatsii i tekhnicheskoy pomoshchi stroitel'stvu.

(Road machinery -- Maintenance and repair)

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行相关时间的当时。

DIKOV, V.A., st. inzh.; KUVYRKIN, N.I., st. inzh.; LITOVCHENKO, Ya.A, st. inzh.; SULOTSKIY, B.P., st. tekhnik; ABDULINA, Kh.M., st. tekhnik; KOLKOTIN, N.M., st. inzh.; SHIROKOVA, G.M., red.; PEREVALYUK, M.V., red.izd-va; BOROVNEV, N.K., tekhn. red.;

[Instructions for the capital repair of machinery used in construction] Ukazaniia po kapital'nomu remontu mashin, zaniatykh v stroitel'stve-(U5-62). Moskva, Gosstroiizdat, 1963. No.4. [Technical specifications for major repairs on excavators with a shovel capacity of 0.35 m³; excavators E-255, E-353, E-257, E-358, E-301, and E-B52] Tekhnicheskie usloviia na kapital'nyi remont ekskavatorov s kovshom emkost'iu do 0,35 m³: ekskavatory E-255, E-353, E-257, E-258, E-301, E-352. 180 p. No.5. [Technical specifications for major repairs on excavators with a shovel capacity of 0.5': excavators E-505, E-505A] Tekhnicheskie usloviia na kapital'nyi remont ekskavatorov s kovshom emkost'iu 0,5 m²: ekskavatory E-505, E-505A. 146 p. (MIRA 16:8)

1. Akademiya stroitel'stva i arkhitektury SSSR. Institut organizatsii, mekhanizatsii i tekhnicheskoy pomoshchi stroitel'stvu. (Excavating machinery--Maintenance and repair)

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LITOVCHENKO, Ye. T.

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"Antigenic and Immunogenic Properties of the Individual Component Farts of Bacterium Paratyphosum A. " Cand Med Sci, Ukrainian Inst of Epidemiology and Microbiology, Kiev, 1953. (RZhBiol, No 7, Apr 55)

SO: Sum. No. 704, 2 Nov 55 - Survey of Scientific and Technical Dissertations Defended at USSR Higher Educational Institutions (16).

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USSR/Micr Anim	obiology. Microbes Pathogenic for Man and F als	
Abs Jour	: Ref Zhur-Biol., No 13, 1958, 57647	
Luthor	: Yelshina M. O., Zaydenberg Ye. G., Zatulovs- kiy B. G., Litovchenko Ye. T., Shubs Z. V.	
Inst Title	: Not given : On Atypical Strains of Microbes of the Coli Group Isolated from Healthy Persons	
Orig Pub	: Mikrobiol. zh., 1957, 19, No 2, 43-48	
Abstract	: In the course of bacteriological investigation of 72,342 practically healthy persons for dy- sentery, 265 atypical cultures (0.3% were iso- lated from the bacillus vectors (0.9%). 256 of the 265 atypical strains belonged to the non- agglutinating group; the remainder agglutinated with the Sonne and Flexner sera, but were	
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USSR/Microbiology, Microbes Pathogenic for Man and F Animals Abs Jour ; Ref Zhur-Biol., No 13, 1958, 57647 : atypical in their biochemical properties. 98 Abstract atypical strains were studied in detail. By the use of various methods---passages through meatpeptone media, bile bullion, organism of mice-it was possible to identify a part of the cul-tures. Particularly useful for the purposes of identification of atypical strains, in the authors' opinion, is the diagnostic method of 0 cultivating cultures on a synthetic medium with or without nicotinic acid, which they proposed; with the help of this method they succeeded in relating most of the atypical strains they had studied to the coli bacillus. Card 2/2

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LIFOVCHENKO, Yu.V.

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> Experimental studies on losses of flood runoff during the subsidence of high waters; following the termination of the rain. Prats: Od. un. zbir. mol. vchen. un. 148 no.3:327-335 '58 (MIRA 13:3) (Runoff)

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ACC NRI AP6021797 (A) SOU INVENTORS: Paton, V. Ye.; Esibyan, E. M.; Svetsinskiy, A. S.; Litovchuk, V. B.	RCE CODE: UH/OL13/66/000/012/0061/0062 Shnaydor, B. I.; Mutsenko, B. S.;
ORG: none TITLE: A dovice for arc welding under argo Institute of Electric Welding im. Ye. O. Pa SOURCE: Isobreteniya, promyshlennyye obraz TOPIC TAGS: welding, arc welding, inert ga technology ABSTRACT: This Author Certificate present capillary and thin-walled tubes of small d machanism. feeding and positioning rolers	tey, tovarnyye snaki, no. 12, 1900, 01-01 as welding, welding equipment, welding a device for arc welding (under argon) of immeters. The device contains a driving a torch, and a protecting chamber (see
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KALININ, N.V.; LIJOVINSKIY, A.K.

Investigating the rigidity of the gear-rolling head for rolling low-module gear wheels on automatic multispindie lathes. Priborostroenie no.l:18 Ja '65. (MIRA 18:3)

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TLE: Technologi	cal peculiarities of	the process of cold	i shaping of small	l gears	·
WRCE: Priborost	royeniye, no. 3, 1964	, 14-18			
PIC TAGS: gear old gear rolling	shaping, gear rolling	, small pitch gear	, multispindle la	the,	
itomatic multiple eeth may be made the gear shaping h	ssion of cold rolling spindle machine (124 on this machine to th ead may be adjusted i sting should be done of rolled gears and	10-6). Small stool 10 eighth class of 10r various gear pi 10n this machine fo	gears with strai accuracy (GOST 91 tches and numbers r broadening the	gnc 78-58). of sizes	
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d configuration	figures.		$\mathcal{L} = \left\{ \begin{array}{c} 1 \\ 1 \\ 1 \\ 1 \\ 1 \\ 1 \\ 1 \\ 1 \\ 1 \\ 1 $		
son: rutusi o d configuration ig. art. has: (SOCIATION: non	figures.			• • • • •	

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MARGULIS, V.S.; LITOVKA, A.V.

NH H H H H H H H H H H

Technical and economic indices of ore grinding at mining and ore dressing combines of the Krivoy Rog Basin. Gor. zhur. no.7:62-67 J^1 '63. (MIRA 16:8)

1. Institut Mekhanobrchermet, Krivoy Rog.

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